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## INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Complete if Known					
Application Number 10/590,204					
§371 Filing Date	May 4, 2007				
First Named Inventor	Simon BATES				
Art Unit	1797				
Examiner Name	Bryan T. Kilpatrick				
Attorney Docket Number	09013.0010-00000				

	U.S. PATENTS AND PUBLISHED U.S. PATENT APPLICATIONS				
Examiner	Cite	Document Number	Issue or	Name of Patentee or	Pages, Columns, Lines, Where
Initials	No.¹	Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Applicant of Cited Document	Relevant Passages or Relevant Figures Appear

Note: Submission of copies of U.S. Patents and published U.S. Patent Applications is not required.

	FOREIGN PATENT DOCUMENTS					
Examiner Initials	Cite No. <sup>1</sup>	Foreign Patent Document  Country Code <sup>3</sup> Number <sup>4</sup> Kind Code <sup>5</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	Translation <sup>6</sup>

		NONPATENT LITERATU	RE DOCUMENTS		
Examiner Initials No. Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.				Translation <sup>6</sup>	
000000000000000000000000000000000000000		Office Action from LLS Application 11/525 930 dated A	oril 282009	000000000000000000000000000000000000000	>>>>>>>>>
000000000000000000000000000000000000000	2	Office Action from U.S. Application 11/525,930 dated Ja	nuary 20, 2010.	000000000000000000000000000000000000000	000000000000000000000000000000000000000
/B.K./	3	Schmidt, M. U., "The role of qualitative and quantitative of X-Ray Power Diffraction," <u>URL:http://www.anorg.chel</u> (2006).			
/B.K./	4	Petkov, V., et al., "High-resolution atomic distribution ful diffraction," Journal of Non-Crystalline Solids, 293-295:7	nctions of disordered materials b 726-730 (2001).	oy high-energy X-ray	
Examiner Signature		/Bryan Kilpatrick/ (08/02/2010)	Date Considered	08/02/2010	

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